Product data sheet

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a SOT78 plastic package intended for use in applications requiring good bidirectional blocking voltage capability and high thermal cycling performance.

2. Features and benefits

- Good bidirectional blocking voltage capability
- High thermal cycling performance

3. Applications

- Ignition circuits
- Motor control
- · Protection circuits
- Voltage regulation

4. Quick reference data

Table 1. Quick reference data

reference data						
Parameter	Conditions		Min	Тур	Max	Unit
repetitive peak off- state voltage			-	-	650	V
repetitive peak reverse voltage			-	-	650	V
non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5		-	-	100	Α
	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms		-	-	110	Α
junction temperature			-	-	125	°C
average on-state current	half sine wave; T _{mb} ≤ 109 °C; <u>Fig. 1</u>		-	-	7.5	Α
RMS on-state current	half sine wave; $T_{mb} \le 109 ^{\circ}\text{C}$; $\overline{\text{Fig. 2}}$; $\overline{\text{Fig. 3}}$		-	-	12	Α
eristics						
gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 7$		-	2	15	mA
acteristics						
rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); expoential waveform; Fig. 12		200	1000	-	V/µs
	repetitive peak off- state voltage repetitive peak reverse voltage non-repetitive peak on- state current junction temperature average on-state current RMS on-state current eristics gate trigger current acteristics rate of rise of off-state	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{ c c c } \hline \textbf{Parameter} & \textbf{Conditions} \\ \hline \textbf{repetitive peak off-state voltage} \\ \hline \textbf{repetitive peak reverse} \\ \hline \textbf{voltage} \\ \hline \textbf{non-repetitive peak on-state current} \\ \hline & \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} \\ \hline \textbf{t}_p = 10 \text{ms; Fig. 4; Fig. 5} \\ \hline \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} \\ \hline \textbf{t}_p = 8.3 \text{ms} \\ \hline \textbf{junction temperature} \\ \hline \textbf{average on-state} \\ \hline \textbf{current} \\ \hline \textbf{RMS on-state current} \\ \hline \textbf{RMS on-state current} \\ \hline \textbf{balf sine wave; T}_{mb} \leq 109 ^{\circ}\text{C; Fig. 1} \\ \hline \textbf{eristics} \\ \hline \textbf{gate trigger current} \\ \hline \textbf{V}_D = 12 \text{V; I}_T = 0.1 \text{A; T}_j = 25 ^{\circ}\text{C; Fig. 7} \\ \hline \textbf{acteristics} \\ \hline \textbf{rate of rise of off-state} \\ \hline \textbf{voltage} \\ \hline \hline \textbf{V}_{DM} = 335 \text{V; T}_j = 125 ^{\circ}\text{C; R}_{GK} = 100 \Omega; \\ \hline \textbf{(V}_{DM} = 67\% \text{of V}_{DRM}); \text{expoential} \\ \hline \end{array}$	$ \begin{array}{ c c c c } \hline \textbf{Parameter} & \textbf{Conditions} & \textbf{Min} \\ \hline \textbf{repetitive peak off-state voltage} & - \\ \hline \textbf{repetitive peak reverse} & - \\ \hline \textbf{voltage} & - \\ \hline \textbf{non-repetitive peak on-state current} & \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - \\ \hline \textbf{t}_p = 10 \text{ms; Fig. 4; Fig. 5} & - \\ \hline \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - \\ \hline \textbf{t}_p = 8.3 \text{ms} & - \\ \hline \textbf{junction temperature} & - \\ \hline \textbf{average on-state} & \textbf{half sine wave; T}_{mb} \leq 109 ^{\circ}\text{C; Fig. 1} & - \\ \hline \textbf{RMS on-state current} & \textbf{half sine wave; T}_{mb} \leq 109 ^{\circ}\text{C; Fig. 2;} & - \\ \hline \textbf{eristics} & \\ \hline \textbf{gate trigger current} & V_D = 12 \text{V; I}_T = 0.1 \text{A; T}_j = 25 ^{\circ}\text{C; Fig. 7} & - \\ \hline \textbf{acteristics} & \\ \hline \textbf{rate of rise of off-state} & V_{DM} = 335 \text{V; T}_j = 125 ^{\circ}\text{C; R}_{GK} = 100 \Omega; \\ \hline \textbf{(V}_{DM} = 67\% \text{of V}_{DRM}); \text{expoential} & 200 \\ \hline \end{array}$	$ \begin{array}{ c c c c } \hline \textbf{Parameter} & \textbf{Conditions} & \textbf{Min} & \textbf{Typ} \\ \hline \textbf{repetitive peak off-state voltage} & - & - & - \\ \hline \textbf{repetitive peak reverse voltage} & - & - & - \\ \hline \textbf{non-repetitive peak on-state current} & \textbf{half sine wave; $T_{j(init)} = 25 ^{\circ}$C; } \\ \hline \textbf{t}_p = 10 \text{ms; } \textbf{Fig. 4; } \textbf{Fig. 5} \\ \hline \textbf{half sine wave; $T_{j(init)} = 25 ^{\circ}$C; } \\ \hline \textbf{t}_p = 8.3 \text{ms} \\ \hline \textbf{junction temperature} & - & - \\ \hline \textbf{average on-state current} & \textbf{half sine wave; $T_{mb} \le 109 ^{\circ}$C; $\textbf{Fig. 1}$} & - & - \\ \hline \textbf{RMS on-state current} & \textbf{half sine wave; $T_{mb} \le 109 ^{\circ}$C; $\textbf{Fig. 2}$; } & - & - \\ \hline \textbf{Fig. 3} & - & - \\ \hline \textbf{eristics} \\ \hline \textbf{gate trigger current} & V_D = 12 \text{V; } I_T = 0.1 \text{A; } T_j = 25 ^{\circ}$C; $\textbf{Fig. 7}$} & - & 2 \\ \hline \textbf{acteristics} \\ \hline \textbf{rate of rise of off-state voltage} & V_{DM} = 335 \text{V; } T_j = 125 ^{\circ}$C; $R_{GK} = 100 \Omega$; } \\ \hline \textbf{(V}_{DM} = 67\% \text{of V}_{DRM}); \text{expoential} \\ \hline \end{array}$	$ \begin{array}{ c c c c } \hline \textbf{Parameter} & \textbf{Conditions} & \textbf{Min} & \textbf{Typ} & \textbf{Max} \\ \hline \textbf{repetitive peak off-state voltage} & - & - & 650 \\ \hline \textbf{repetitive peak reverse} & - & - & 650 \\ \hline \textbf{non-repetitive peak on-state current} & \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - & - & 100 \\ \hline \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - & - & 110 \\ \hline \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - & - & 125 \\ \hline \textbf{half sine wave; T}_{j(init)} = 25 ^{\circ}\text{C;} & - & - & 125 \\ \hline \textbf{average on-state} & \textbf{half sine wave; T}_{mb} \leq 109 ^{\circ}\text{C; Fig. 1} & - & - & 7.5 \\ \hline \textbf{RMS on-state current} & \textbf{half sine wave; T}_{mb} \leq 109 ^{\circ}\text{C; Fig. 2;} & - & - & 12 \\ \hline \textbf{eristics} & \\ \hline \textbf{gate trigger current} & \textbf{V}_D = 12 \textbf{V; I}_T = 0.1 \textbf{A; T}_j = 25 ^{\circ}\text{C; Fig. 7} & - & 2 & 15 \\ \hline \textbf{acteristics} & \\ \hline \textbf{rate of rise of off-state} & \textbf{V}_{DM} = 335 \textbf{V; T}_j = 125 ^{\circ}\text{C; R}_{GK} = 100 \Omega; \\ \hline \textbf{V}_{DM} = 67\% \text{of V}_{DRM}); \text{expoential} & 200 & 1000 - \\ \hline \end{array}$

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5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	mb	А Ы К
2	Α	anode	├	G sym037
3	G	gate		Symosi
mb	A	mounting base; connected to anode		
			TO-220AB (SOT78)	

6. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
BT151-650C	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78		

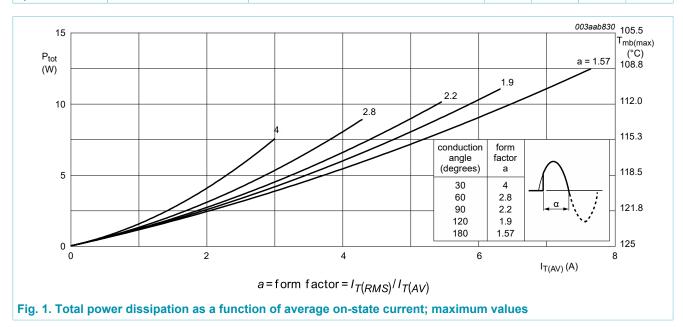
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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	650	V
V_{RRM}	repetitive peak reverse voltage		-	650	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 109 °C; <u>Fig. 1</u>	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 109 ^{\circ}\text{C}$; Fig. 2; Fig. 3	-	12	Α
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5	-	100	Α
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms	-	110	Α
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	50	A²s
dl _T /dt	rate of rise of on-state current	I _G = 30 mA	-	50	A/µs
I _{GM}	peak gate current		-	2	Α
V_{RGM}	peak reverse gate voltage		-	5	V
P _{GM}	peak gate power		-	5	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.5	W
T _{stg}	storage temperature		-40	150	°C
T _j	junction temperature		-	125	°C



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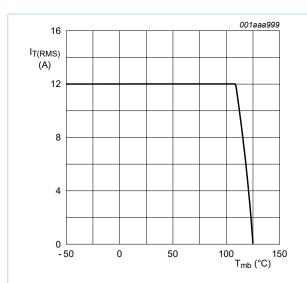


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values

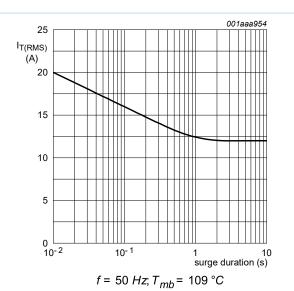


Fig. 3. RMS on-state current as a function of surge duration; maximum values

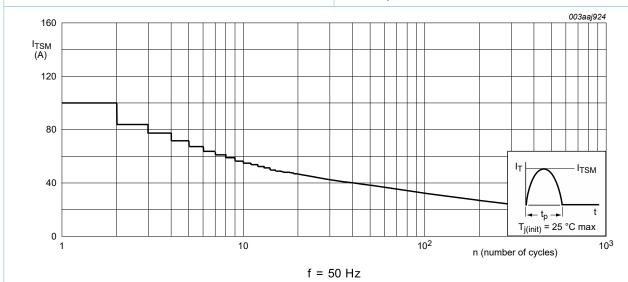
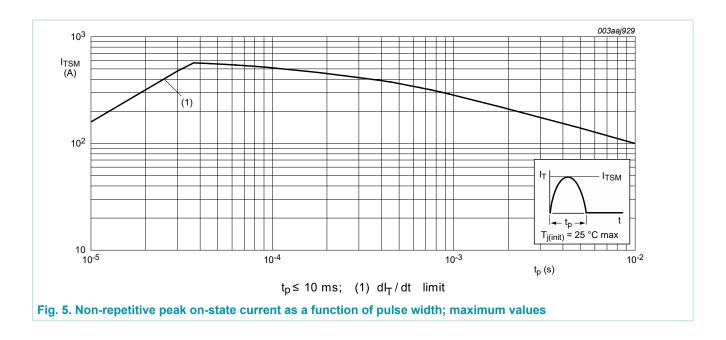


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	-	1.3	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	in free air	-	60	-	K/W

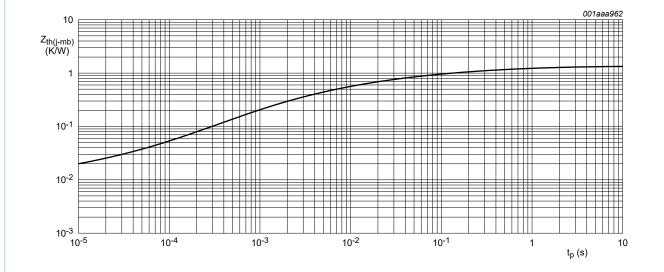


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse width

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9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	2	15	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 8$	-	10	40	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	7	20	mA
V _T	on-state voltage	I _T = 23 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.44	1.75	V
V _{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11	-	0.6	1.5	V
		$V_D = 500 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C};$ Fig. 11	0.25	0.4	-	V
I _D	off-state current	V _D = 500 V; T _j = 125 °C	-	0.1	0.5	mA
I _R	reverse current	V _R = 500 V; T _j = 125 °C	-	0.1	0.5	mA
Dynamic ch	naracteristics		'			
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω; $(V_{DM}$ = 67% of V_{DRM}); expoential waveform; Fig. 12	200	1000	-	V/µs
		V_{DM} = 335 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	50	130	-	V/µs
t _{gt}	gate-controlled turn-on time	I_{TM} = 40 A; V_D = 500 V; I_G = 0.1 A; dI_G/dt = 5 A/µs; T_j = 25 °C	-	2	-	μs
t _q	commutated turn-off time	$V_{DM} = 335 \text{ V; } T_j = 125 \text{ °C; } I_{TM} = 20 \text{ A; } V_R = 25 \text{ V; } (dI_T/dt)_M = 30 \text{ A/µs; } dV_D/dt = 50 \text{ V/µs; } R_{GK(ext)} = 100 \Omega; (V_{DM} = 67\% \text{ of } V_{DRM})$	-	70	-	μs

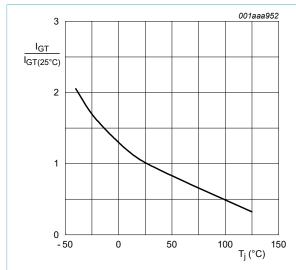


Fig. 7. Normalized gate trigger current as a function of junction temperature

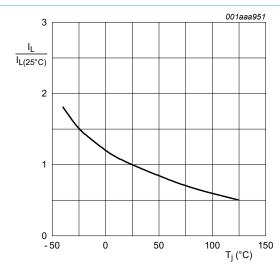


Fig. 8. Normalized latching current as a function of junction temperature

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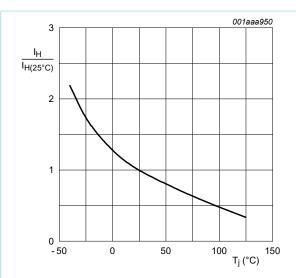
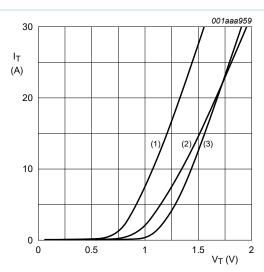


Fig. 9. Normalized holding current as a function of junction temperature



 V_{o} = 1.06 V; R_{s} = 0.0304 Ω (1) T_{j} = 125 °C; typical values (2) T_{j} = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

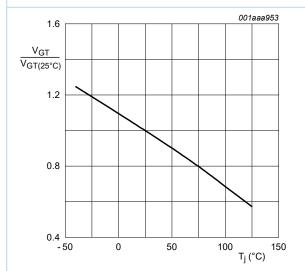
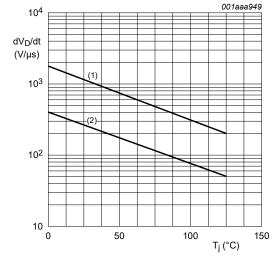


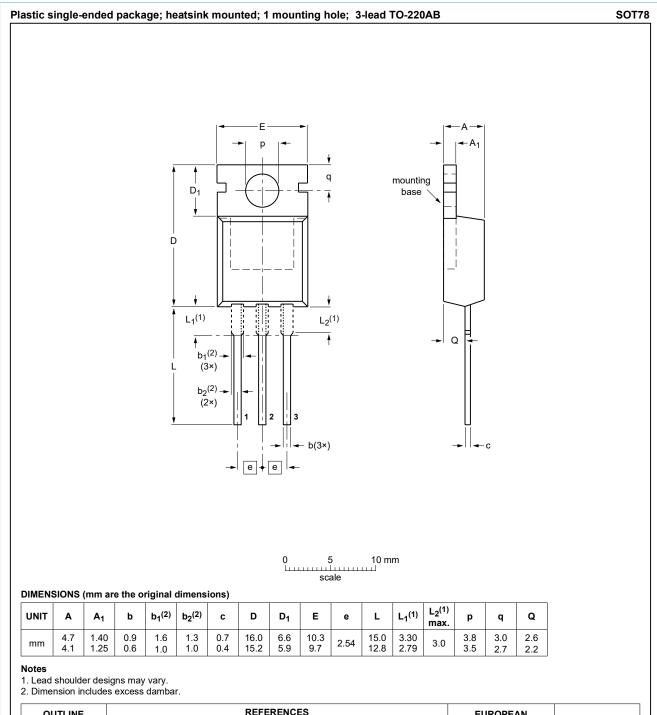
Fig. 11. Normalized gate trigger voltage as a function of junction temperature



(1) $R_{GK} = 100 \Omega$; (2) gate open circuit

Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

10. Package outline



OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT78		3-lead TO-220AB	SC-46			08-04-23 08-06-13
					- 1	

Fig. 13. Package outline TO-220AB (SOT78)

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11. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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Date of release: 22 February 2018

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